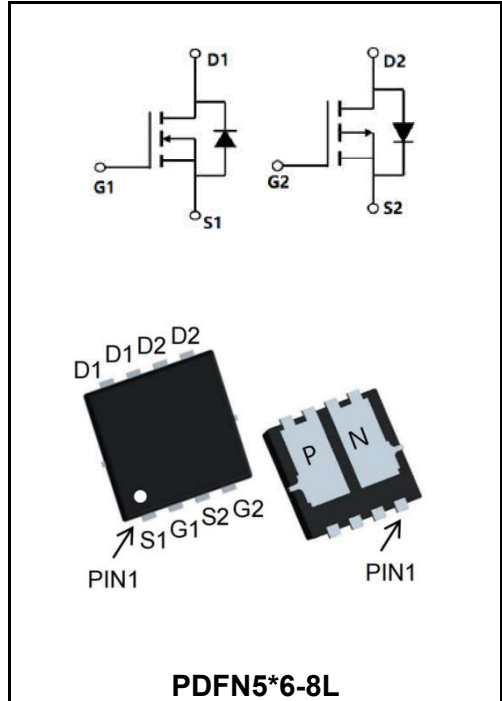


**60V N+P-CHANNEL ENHANCEMENT MODE MOSFET**
**MAIN CHARACTERISTICS**

$I_D$	10A
$V_{DSS}$	60V
$R_{DS(on)-typ}(@V_{GS}=10V)$	< 40mΩ (Type:35 mΩ)
$I_D$	-9.5A
$V_{DSS}$	-60V
$R_{DS(on)-typ}(@V_{GS}=-10V)$	< 70mΩ (Type:55 mΩ)


**Application**

- ◆ Battery protection
- ◆ Load switch
- ◆ Uninterruptible power supply

**Product Specification Classification**

Part Number	Package	Marking	Pack
YFW10G06NF	PDFN5*6-8L	YFW 10G06NF XXXXX	5000PCS/Tape

**Maximum Ratings at Tc=25°C unless otherwise specified**

Characteristics	Symbols	Value		Units
		N-Ch	P-Ch	
Drain-Source Voltage	$V_{DS}$	60	-60	V
Gate - Source Voltage	$V_{GS}$	±20	±20	V
Continuous Drain Current, $V_{GS} @ 10V^1 @ T_A=25^\circ C$	$I_D$	10	-9.5	A
Continuous Drain Current, $V_{GS} @ 10V^1 @ T_A=70^\circ C$	$I_D$	5.2	-4.3	A
Pulsed Drain Current <sup>2</sup>	$I_{DM}$	30	-27	A
Single Pulse Avalanche Energy <sup>3</sup>	$E_{AS}$	25.5	35.3	mJ
Avalanche Current	$I_{AS}$	22.6	-26.6	A
Total Power Dissipation <sup>4</sup> @ $T_A=25^\circ C$	$P_D$	1.5	1.5	W
Storage Temperature Range	$T_{STG}$	-55 to +150		°C
Operating Junction Temperature Range	$T_J$	-55 to +150		°C
Thermal Resistance Junction-Ambient <sup>1</sup>	$R_{\theta JA}$	85		°C/W
Thermal Resistance Junction-Case <sup>1</sup>	$R_{\theta JC}$	36		°C/W

**N-Channel Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)**

Characteristics	Test Condition	Symbols	Min	Typ	Max	Units
Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	<b>BV<sub>DSS</sub></b>	60	66	-	<b>V</b>
BVDSS Temperature Coefficient	Reference to 25 °C , I <sub>D</sub> =1mA	<b>ΔBV<sub>DSS</sub>/ΔT<sub>J</sub></b>	-	0.063	-	<b>V/°C</b>
Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V, I <sub>D</sub> =4A	<b>R<sub>DS(ON)</sub></b>	-	35	40	<b>mΩ</b>
	V <sub>GS</sub> =4.5V, I <sub>D</sub> =2A		-	38	45	
Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA	<b>V<sub>GS(th)</sub></b>	1.2	1.6	2.5	<b>V</b>
V <sub>GS(th)</sub> Temperature Coefficient		<b>ΔV<sub>GS(th)</sub></b>	-	-5.24	-	<b>mV/°C</b>
Drain-Source Leakage Current	V <sub>DS</sub> =48V, V <sub>GS</sub> =0V T <sub>J</sub> =25°C	<b>I<sub>DSS</sub></b>	-	-	1	<b>uA</b>
	V <sub>DS</sub> =48V, V <sub>GS</sub> =0V, T <sub>J</sub> =55°C		-	-	5	
Gate-Source Leakage Current	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	<b>I<sub>GSS</sub></b>	-	-	±100	<b>nA</b>
Forward Transconductance	V <sub>DS</sub> = 5V, I <sub>D</sub> = 4A	<b>g<sub>fs</sub></b>	-	21	-	<b>S</b>
Gate Resistance	V <sub>DS</sub> =0V, V <sub>GS</sub> =0V, f=1MHz	<b>R<sub>g</sub></b>	-	3.2	-	<b>Ω</b>
Total Gate Charge(4.5V)	V <sub>DS</sub> =48V V <sub>GS</sub> =4.5V I <sub>D</sub> =4A	<b>Q<sub>g</sub></b>	-	12.6	-	<b>nC</b>
Gate-Source Charge		<b>Q<sub>gs</sub></b>	-	3.2	-	
Gate-Drain Charge		<b>Q<sub>gd</sub></b>	-	6.3	-	
Turn-on delay time	V <sub>DD</sub> =30V V <sub>GS</sub> =10V R <sub>G</sub> = 3.3Ω I <sub>D</sub> = 4A	<b>t<sub>d(on)</sub></b>	-	8	-	<b>ns</b>
Rise Time		<b>T<sub>r</sub></b>	-	14.2	-	
Turn-Off Delay Time		<b>t<sub>d(OFF)</sub></b>	-	24.4	-	
Fall Time		<b>t<sub>f</sub></b>	-	4.6	-	
Input Capacitance	V <sub>DS</sub> =15V V <sub>GS</sub> =0V f=1MHz	<b>C<sub>iss</sub></b>	-	1378	-	<b>pF</b>
Output Capacitance		<b>C<sub>oss</sub></b>	-	86	-	
Reverse Transfer Capacitance		<b>C<sub>rss</sub></b>	-	64	-	
Continuous Source Current <sup>1,5</sup>	V <sub>G</sub> =V <sub>D</sub> =0V, Force Current	<b>I<sub>S</sub></b>	-	-	4.8	<b>A</b>
Pulsed Source Current <sup>2,5</sup>		<b>I<sub>SM</sub></b>	-	-	9.6	<b>A</b>
Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V, I <sub>S</sub> =1A, T <sub>J</sub> =25°C	<b>V<sub>SD</sub></b>	-	-	1.2	<b>V</b>

Note :

- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%
- 3.The EAS data shows Max. rating . The test condition is V<sub>DD</sub>=-25V,V<sub>GS</sub>=-10V,L=0.1mH,I<sub>AS</sub>=-26.6A
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub> , in real applications , should be limited by total power dissipation

**P-Channel Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)**

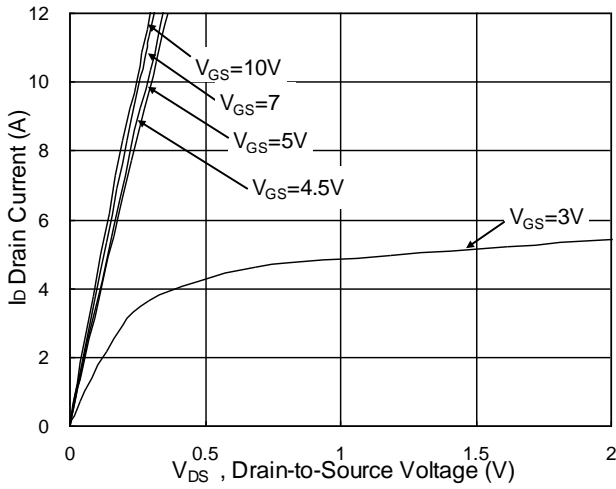
Characteristics	Test Condition	Symbols	Min	Typ	Max	Units
Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =-250uA	<b>BV<sub>DSS</sub></b>	-60	-66	-	<b>V</b>
BVDSS Temperature Coefficient	Reference to 25°C, I <sub>D</sub> =-1mA	<b>ΔBV<sub>DSS</sub>/ΔT<sub>J</sub></b>	-	-0.03	-	<b>V/°C</b>
Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =-10V, I <sub>D</sub> =-3A	<b>R<sub>DS(ON)</sub></b>	-	55	70	<b>mΩ</b>
	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-2A		-	75	105	
Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250uA	<b>V<sub>GS(th)</sub></b>	-1.2	-1.5	-2.5	<b>V</b>
V <sub>GS(th)</sub> Temperature Coefficient		<b>ΔV<sub>GS(th)</sub></b>	-	4.56	-	<b>mV/°C</b>
Drain-Source Leakage Current	V <sub>DS</sub> =-48V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C	<b>I<sub>DSS</sub></b>	-	-	1	<b>uA</b>
	V <sub>DS</sub> =-48V, V <sub>GS</sub> =0V, T <sub>J</sub> =55°C		-	-	5	
Gate-Source Leakage Current	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	<b>I<sub>GSS</sub></b>	-	-	±100	<b>nA</b>
Forward Transconductance	V <sub>DS</sub> = -5V, I <sub>D</sub> = -3A	<b>g<sub>fs</sub></b>	-	15	-	<b>S</b>
Gate Resistance	V <sub>DS</sub> =0V, V <sub>GS</sub> =0V, f=1MHz	<b>R<sub>g</sub></b>	-	13.5	-	<b>Ω</b>
Total Gate Charge(-4.5V)	V <sub>DS</sub> =-48V V <sub>GS</sub> =-4.5V I <sub>D</sub> =-3A	<b>Q<sub>g</sub></b>	-	9.86	-	<b>nC</b>
Gate-Source Charge		<b>Q<sub>gs</sub></b>	-	3.1	-	
Gate-Drain Charge		<b>Q<sub>gd</sub></b>	-	2.95	-	
Turn-on delay time	V <sub>DD</sub> =-15V V <sub>GS</sub> =-10V R <sub>G</sub> = 3.3Ω I <sub>D</sub> =-1A	<b>t<sub>d(on)</sub></b>	-	28.8	-	<b>ns</b>
Rise Time		<b>T<sub>r</sub></b>	-	19.8	-	
Turn-Off Delay Time		<b>t<sub>d(OFF)</sub></b>	-	60.8	-	
Fall Time		<b>t<sub>f</sub></b>	-	7.2	-	
Input Capacitance	V <sub>DS</sub> =-15V V <sub>GS</sub> =0V f=1MHz	<b>C<sub>iss</sub></b>	-	1447	-	<b>pF</b>
Output Capacitance		<b>C<sub>oss</sub></b>	-	97.3	-	
Reverse Transfer Capacitance		<b>C<sub>rss</sub></b>	-	70	-	
Continuous Source Current <sup>1,5</sup>	V <sub>G</sub> =V <sub>D</sub> =0V, Force Current	<b>I<sub>S</sub></b>	-	-	-3.7	<b>A</b>
Pulsed Source Current <sup>2,5</sup>		<b>I<sub>SM</sub></b>	-	-	-7.5	<b>A</b>
Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V, I <sub>S</sub> =-1A, T <sub>J</sub> =25°C	<b>V<sub>SD</sub></b>	-	-	-1.2	<b>V</b>

Note :

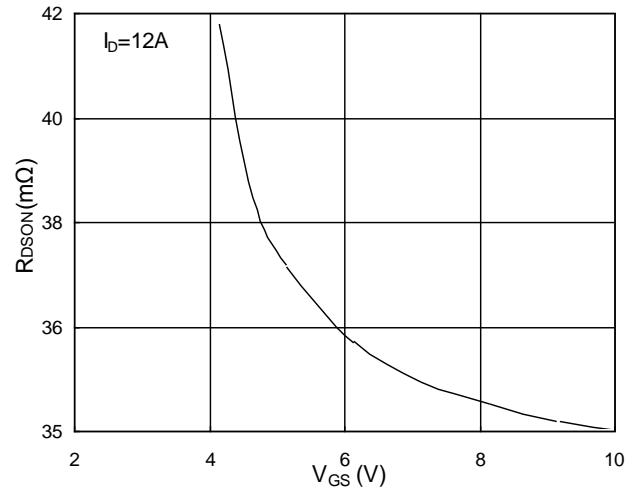
- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width ≅ 300us , duty cycle ≅ 2%
- 3.The EAS data shows Max. rating . The test condition is VDD=25V,VGS=10V,L=0.1mH,IAS=22.6A
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation

**Ratings and Characteristic Curves**

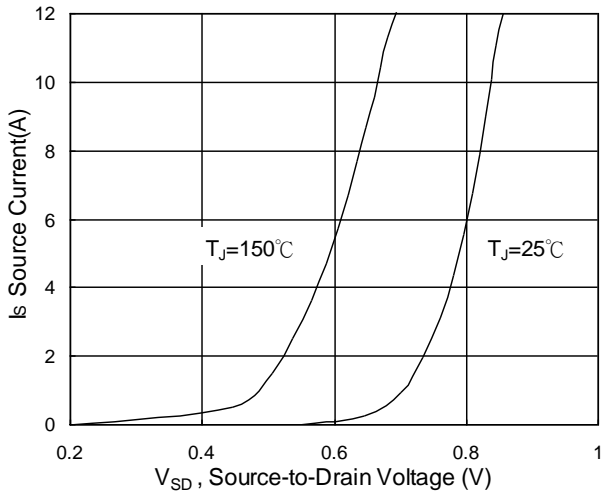
**N-Channel Typical Characteristics**



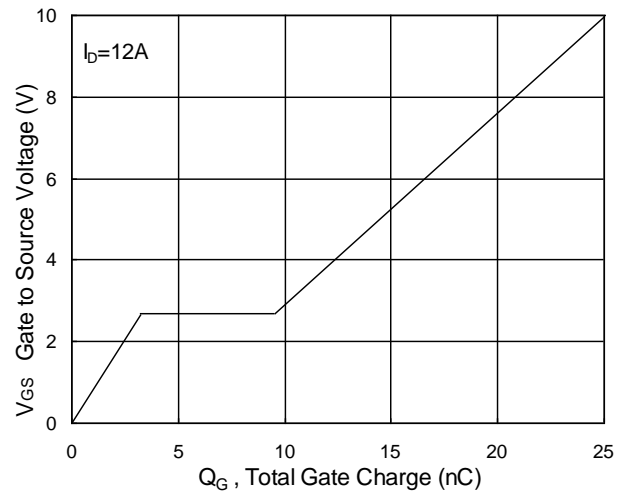
**Fig.1 Typical Output Characteristics**



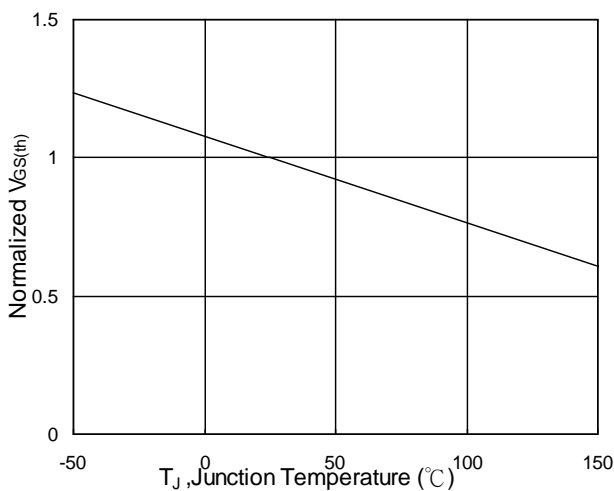
**Fig.2 On-Resistance v.s Gate-Source**



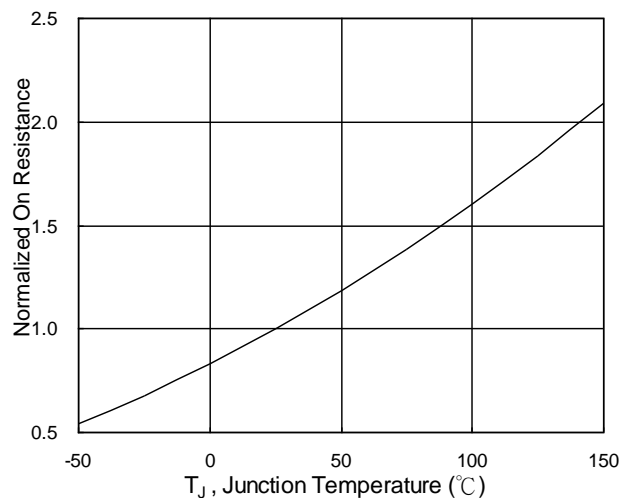
**Fig.3 Forward Characteristics of Reverse**



**Fig.4 Gate-Charge Characteristics**

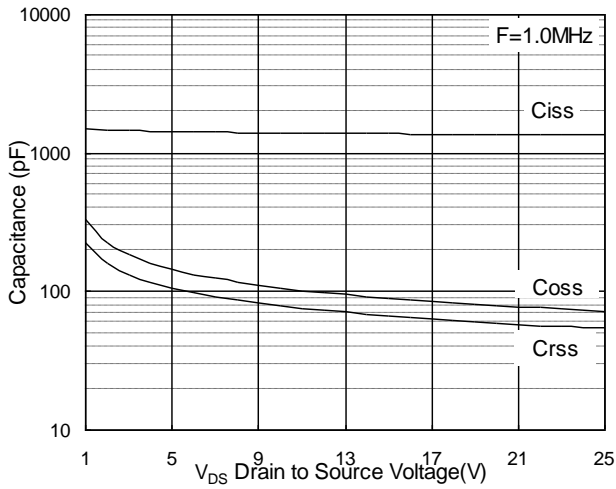


**Fig.5 Normalized  $V_{GS(th)}$  v.s  $T_J$**

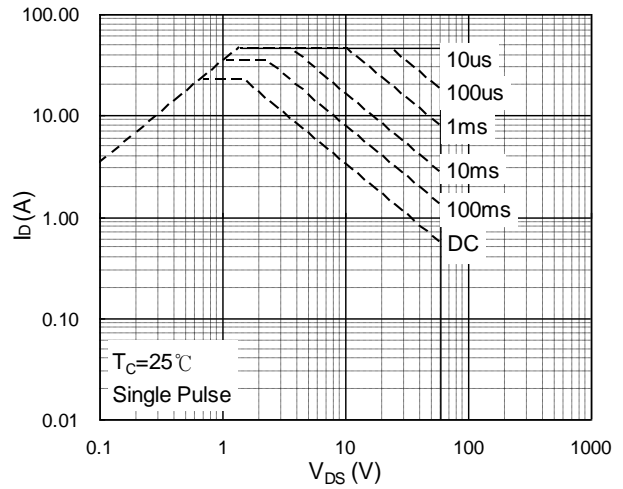


**Fig.6 Normalized  $R_{DS(on)}$  v.s  $T_J$**

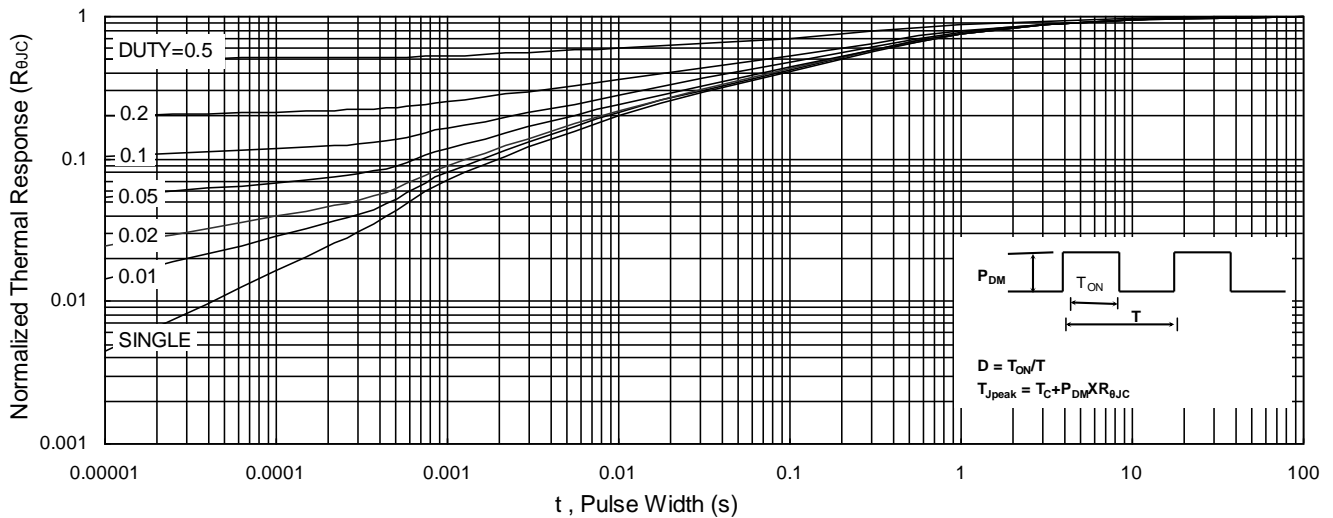
**Ratings and Characteristic Curves**



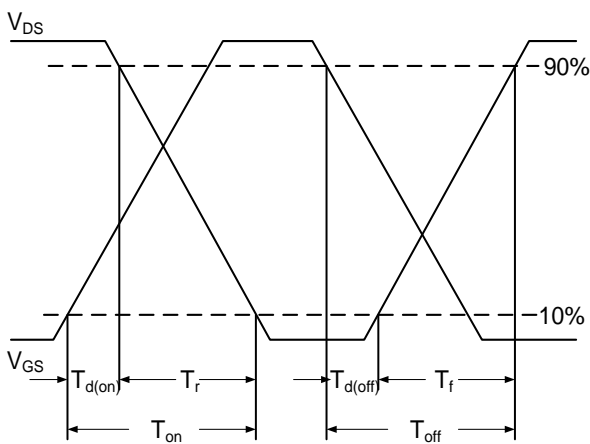
**Fig.7 Capacitance**



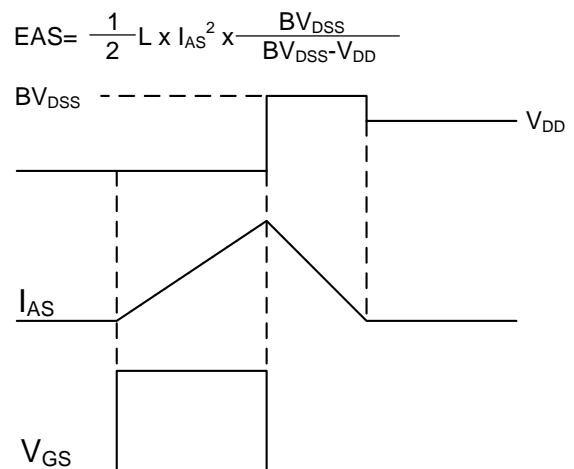
**Fig.8 Safe Operating Area**



**Fig.9 Normalized Maximum Transient Thermal Impedance**



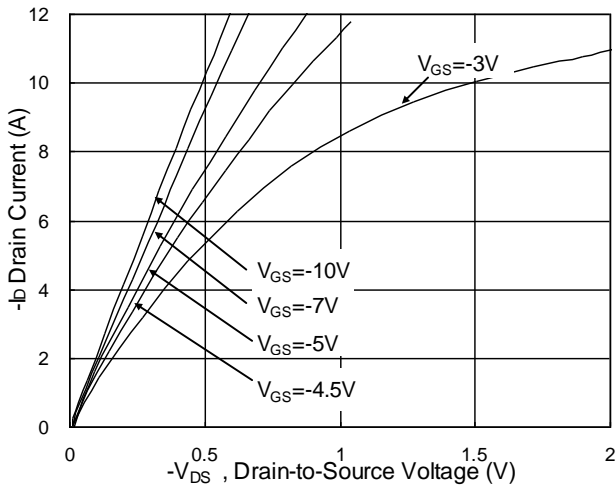
**Fig.10 Switching Time Waveform**



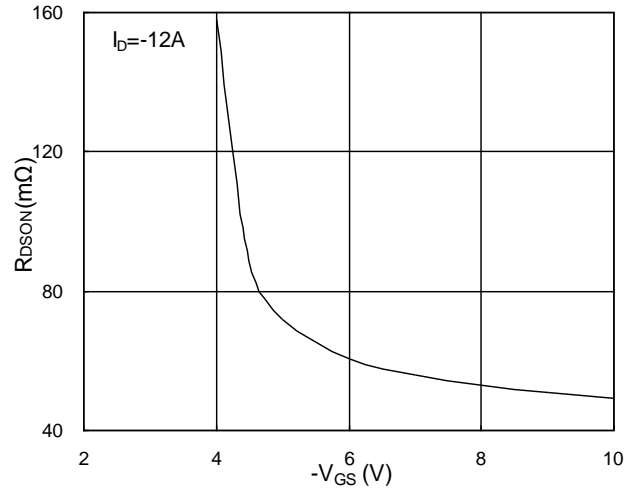
**Fig.11 Unclamped Inductive Waveform**

**Ratings and Characteristic Curves**

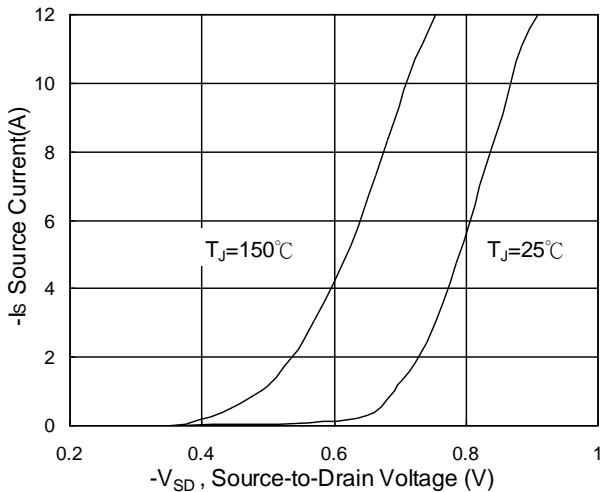
**P-Channel Typical Characteristics**



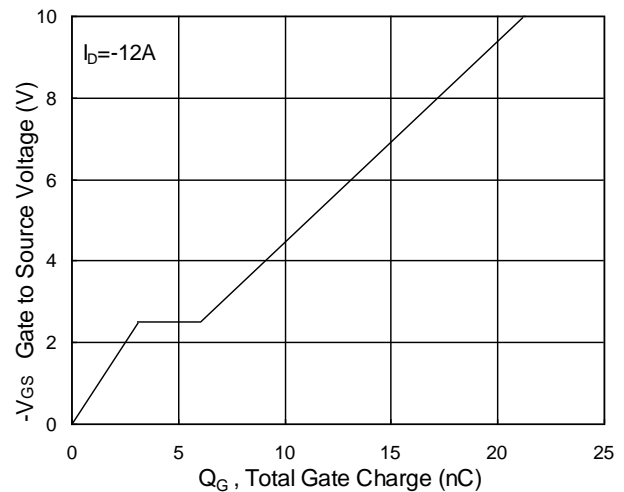
**Fig.1 Typical Output Characteristics**



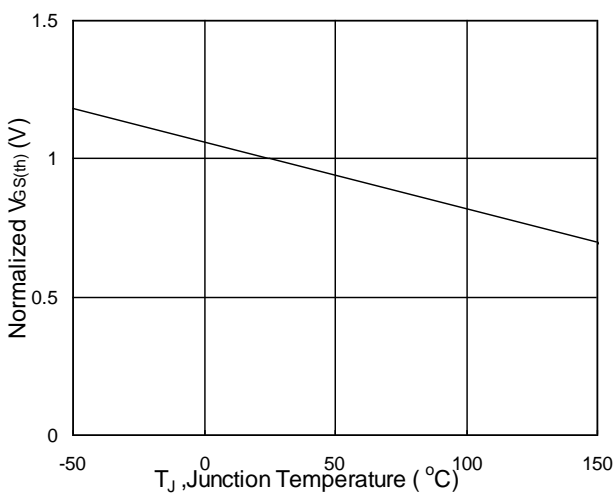
**Fig.2 On-Resistance v.s Gate-Source**



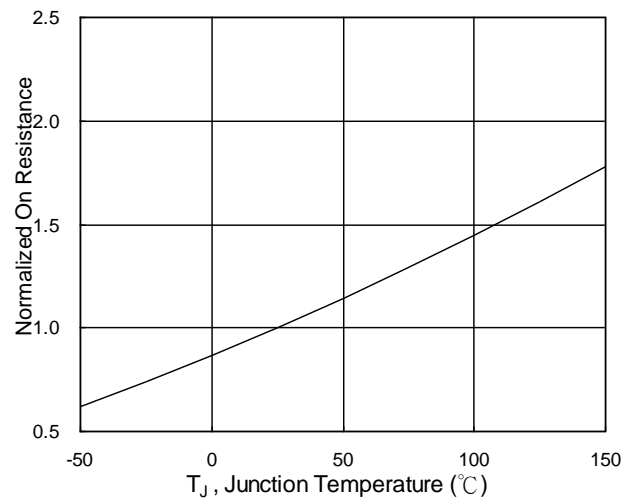
**Fig.3 Forward Characteristics of Reverse**



**Fig.4 Gate-Charge Characteristics**

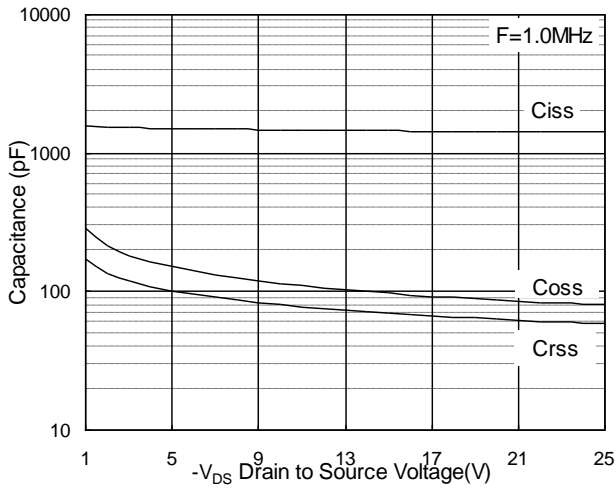


**Fig.5 Normalized  $V_{GS(th)}$  v.s  $T_J$**

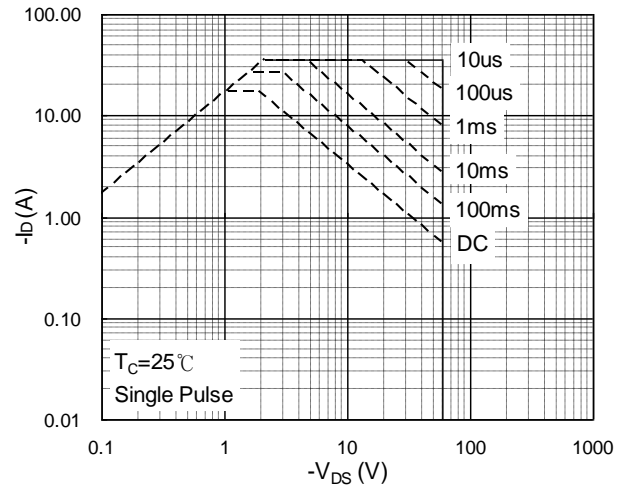


**Fig.6 Normalized  $R_{DS(on)}$  v.s  $T_J$**

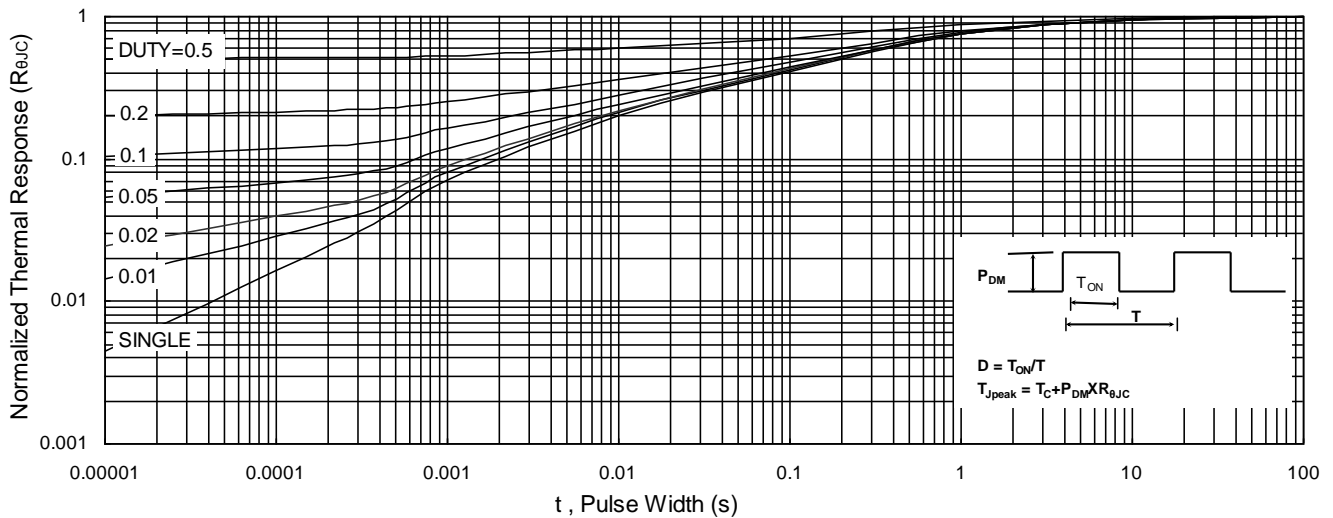
**Ratings and Characteristic Curves**



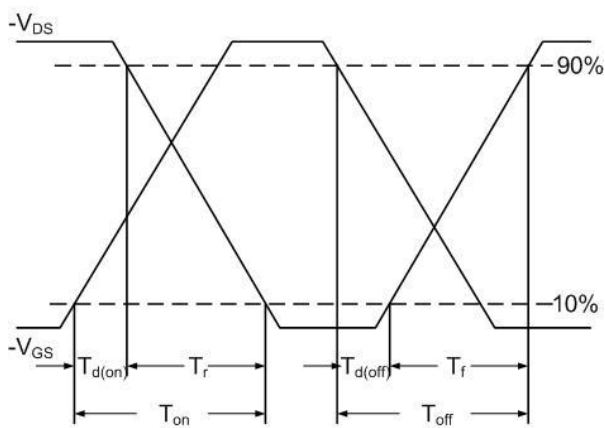
**Fig.7 Capacitance**



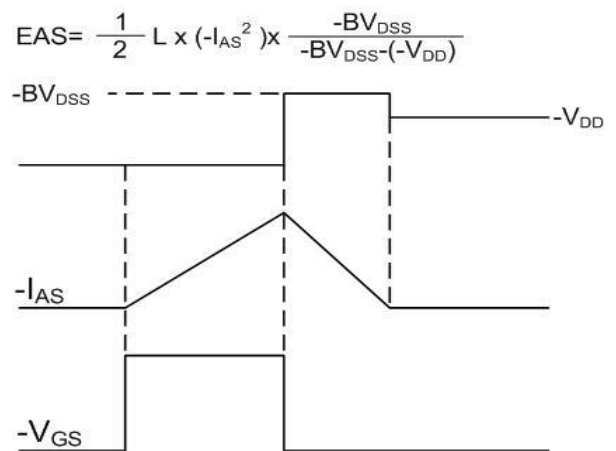
**Fig.8 Safe Operating Area**



**Fig.9 Normalized Maximum Transient Thermal Impedance**

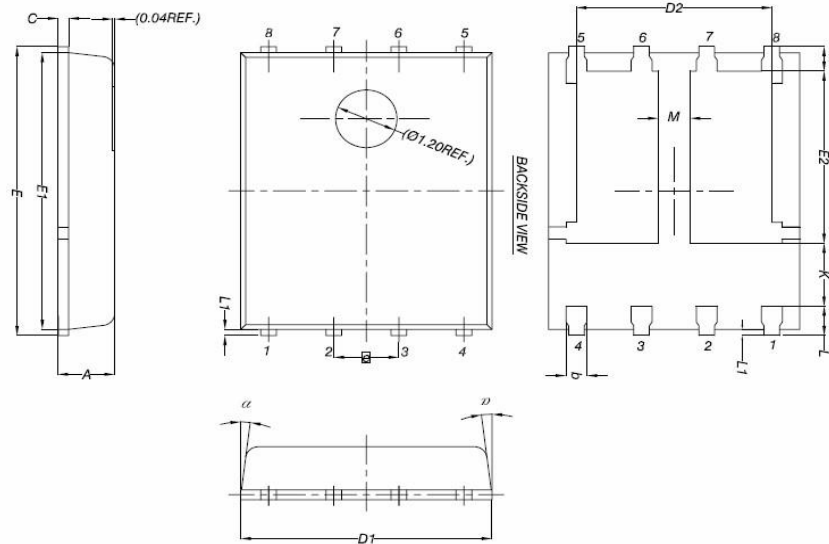


**Fig.10 Switching Time Waveform**



**Fig.11 Unclamped Inductive Waveform**

**PDFN5\*6-8L**



Symbol	Common		
	mm		
	Mim	Nom	Max
A	0.90	1.00	1.10
b	0.33	0.41	0.51
C	0.20	0.25	0.30
D1	4.80	4.90	5.00
D2	3.61	3.81	3.96
E	5.90	6.00	6.10
E1	5.66	5.76	5.83
E2	3.37	3.47	3.58
e	1.27BSC		
H	0.41	0.51	0.61
K	1.10	--	--
L	0.51	0.61	0.71
L1	0.06	0.13	0.20
M	0.50	--	--
a	0°	--	12°